

**IN THE ABSTRACT**

Please replace the abstract with the following new abstract:

The system for testing a semiconductor device (DUT) includes: a socket for receiving a DUT, the socket having pins with ends for making electrical contact with the DUT and opposing ends for making contact with a test board; the test board adjoining the socket, the test board having pin receptacles for receiving the opposing ends of the pins; and measuring means operably coupled to the test board pin receptacles for measuring electrical signals in the DUT.